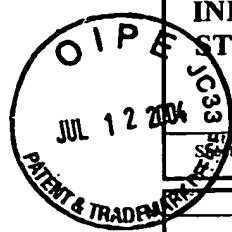


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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (use as many sheets as necessary)				Application Number	10/722,889
				Filing Date	November 26, 2003
				First Named Inventor	James F. Munro
				Art Unit	3622
				Examiner Name	To Be Assigned
				Attorney Docket Number	4484/111
SSen	1	of	2		

**U.S. PATENT DOCUMENTS**

Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	U.S. Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code <sup>2</sup> (if known)				
LDR	1	US-2,234,329		03/11/1941	Wolff	
	2	US-2,433,667		12/30/1947	Hollingsworth	
	3	US-3,365,717		01/23/1968	Holscher	
	4	US-3,503,680		03/31/1970	Schenkerman	
	5	US-3,614,226		10/19/1971	Vergoz	
	6	US-3,630,616		12/28/1971	Everest	
	7	US-3,652,161		03/28/1972	Ross	
	8	US-3,854,133		12/10/1974	Cabion	
	9	US-3,936,824		02/03/1976	Aker	
	10	US-4,140,060		02/20/1979	Brenner	
	11	US-4,146,328		03/27/1979	Hullein	
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	13	US-4,636,068		01/13/1987	Niho	
	14	US-4,654,584		03/31/1987	Gyles	
	15	US-4,657,382		04/14/1987	Busujima	
	16	US-4,699,508		10/13/1987	Bolkow	
	17	US-4,829,172		05/09/1989	Miller	
	18	US-4,880,307		11/14/1989	Endo	
	19	US-5,125,008		06/23/1992	Trawick	
	20	US-5,148,178		09/15/1992	Holzer	
	21	US-5,204,732		04/20/1993	Ohmamuya	
	22	US-5,210,585		05/11/1993	Suzuki	
	23	US-5,260,670		11/09/1993	Ainsworth	
	24	US-5,311,353		05/10/1994	Crawford	
	25	US-5,359,404		10/25/1994	Dunne	
	26	US-5,585,913		12/17/1996	Hariharan	
	27	US-5,619,317		04/08/1997	Oishi	
	28	US-5,652,651		07/29/1997	Dunne	
	29	US-5,745,437		04/28/1998	Wachter	
	30	US-5,880,822		03/09/1999	Kubo	
	31	US-5,889,490		03/30/1999	Wachter	
LDR	32	US-5,977,905		11/02/1999	LeChevalier	

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Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>4</sup>
		Country Code <sup>3</sup> Number <sup>4</sup>	Kind Code <sup>2</sup> (if known)				

Examiner Signature	<i>James F. Munro</i>	Date Considered	1/13/06
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				Application Number	
				Filing Date	
				First Named Inventor	
				Group Art Unit	
				Examiner Name	
Attorney	2	of	2	Attorney Docket Number	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T <sup>2</sup>
LPN	33	Antoniou et al., "Digital Filters: Analysis and Design," <u>McGraw-Hill</u> , 151-154 (1979)			
	34	Born et al., "Principles of Optics," <u>Pergamon Press</u> , 291 (1983)			
	35	Bracewell et al., "The Fourier Transform and its Applications," <u>McGraw-Hill</u> , 356-362 (1978)			
	36	Woodbury et al., "Noninvasive Tank Gauging with Frequency-Modulated Laser Ranging," <u>Sensors</u> , 27-31 (1993)			
	37	Neter et al., "Applied Linear Regression Models," <u>Richard D. Irwin, Inc.</u> , Chapter 14, 466-485 (1983)			
	38	"Real-Time Versus Equivalent-Time Sampling," Tektronix, Inc., [Retrieved from the internet <a href="http://www.tek.com/Measurement/App_Notes/RTvET/ap-RTvET.html">http://www.tek.com/Measurement/App_Notes/RTvET/ap-RTvET.html</a> ], 1-18 (2003)			
	39	"Code of Federal Regulations Title 21 (eye-safety requirements and regulations)," <u>U.S. Food and Drug Administration – Center for Devices and Radiological Health</u> , [Retrieved from the internet <a href="http://www.accessdata.fda.gov/scripts/cdrh/cfdocs/cfcfr/CFRSearch.cfm?FR=1040.10">http://www.accessdata.fda.gov/scripts/cdrh/cfdocs/cfcfr/CFRSearch.cfm?FR=1040.10</a> ] Part 1040, 1-20 (2002)			
	40	Stone, "Index of Refraction of Air," <u>NIST's Engineering Metrology Toolbox WaveLength Calculator</u> , [Retrieved from the internet] <a href="http://patapsco.nist.gov/mel/div821/Wavelength/Documentation.asp">http://patapsco.nist.gov/mel/div821/Wavelength/Documentation.asp</a> , 1-17 (2001)			
LPN	41	Payne et al., "Rangefinder With Fast Multiple Range Capability," <u>Review of Scientific Instruments</u> , 63:3311-3316 (1992)			

Examiner Signature	Luke Yatel Ph	Date Considered	1/13/06
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of

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## Complete if Known

Application Number	10/722,889
Filing Date	November 26, 2003
First Named Inventor	James F. Munro
Art Unit	3622
Examiner Name	To Be Assigned
Attorney Docket Number	4484/111

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LDR	32	US-5,977,905	11/02/1999	LeChevalier	

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		Country Code <sup>3</sup> Number <sup>4</sup>	Kind Code <sup>2</sup> (if known)			

Examiner Signature	Luke Batchiffe	Date Considered	1/13/06
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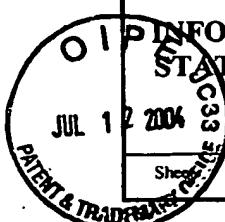
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## OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

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	35	Bracewell et al., "The Fourier Transform and its Applications," <u>McGraw-Hill</u> , 356-362 (1978)	
	36	Woodbury et al., "Noninvasive Tank Gauging with Frequency-Modulated Laser Ranging," <u>Sensors</u> , 27-31 (1993)	
	37	Neter et al., "Applied Linear Regression Models," <u>Richard D. Irwin, Inc.</u> , Chapter 14, 466-485 (1983)	
	38	"Real-Time Versus Equivalent-Time Sampling," Tektronix, Inc., [Retrieved from the internet <a href="http://www.tek.com/Measurement/App_Notes/RTvET/ap-RTvET.html">http://www.tek.com/Measurement/App_Notes/RTvET/ap-RTvET.html</a> ], 1-18 (2003)	
	39	"Code of Federal Regulations Title 21 (eye-safety requirements and regulations)," <u>U.S. Food and Drug Administration - Center for Devices and Radiological Health</u> , [Retrieved from the internet <a href="http://www.accessdata.fda.gov/scripts/cdrh/cfdocs/cfcr/CFRSearch.cfm?FR=1040.10">http://www.accessdata.fda.gov/scripts/cdrh/cfdocs/cfcr/CFRSearch.cfm?FR=1040.10</a> ]	
	40	Stone, "Index of Refraction of Air," <u>NIST's Engineering Metrology Toolbox WaveLength Calculator</u> , [Retrieved from the internet <a href="http://patapsco.nist.gov/mel/div821/Wavelength/Documentation.asp">http://patapsco.nist.gov/mel/div821/Wavelength/Documentation.asp</a> ], 1-17 (2001)	
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